

Application/Control No.	Applicant(s)/Patent under R examination
10/780,844	BACKES ET AL.
Examiner	Art Unit
James D. Ewart	2617

James D. Ewart

	SEARCHED			
Class	Subclass	Date	Examiner	
455	63.1	5/31/2006	JDE	
	63.3			
	434			
	447			
	450-454			
	455			
	463			
	464			
	509			
	515			
	516			
370	329			
	330			
	332			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
obtained class 455 search from Bill Trost	2/7/2006	JDE
Spoke to Steve D'Agosta for search suggestions	2/7/2006	JDE
Obtained search from Vo Nguyen	2/7/2006	JDE

Search Notes	(continued)

Application/Control No.	Applicant(s)/Patent under Reexamination
10/780,844	BACKES ET AL.
Examiner	Art Unit
James D. Ewart	2617

SEARCHED			
Class	Subclass	Date	Examiner
370	338	5/31/2006	JDE
	341	-	
	343		
	431		
	437		
	464		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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